

# Refractive lens design and aberration compensation

Frank Seiboth

frank.Seiboth@desy.de

FS-PETRA, Photon Science, Deutsches Elektronen-Synchrotron DESY

# Refractive lens design and aberration compensation

## Outline:

- Refractive index for x rays
  - Basic lens properties
  - Simple online calculator: [lenscalc.desy.de](http://lenscalc.desy.de)
  - Some application examples
- 
- Lens errors and material impurities
  - Wavefront measurements
  - Design of phase plates for aberration compensation

# The refractive index in the x-ray regime

Derived from phenomenological comparison

- scattering from atoms (form factor)
- transmission with refraction through material

Refractive index n:  $n(\omega) = 1 - \delta + i\beta$

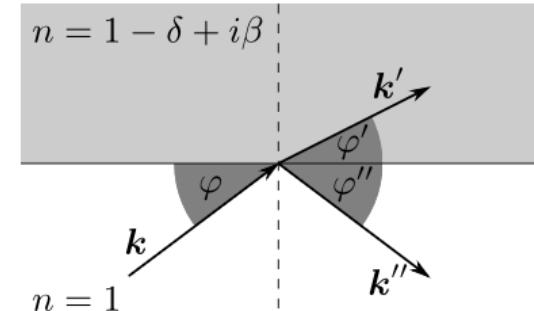
$$\delta = \frac{n_a}{2\pi} r_e \lambda^2 \underbrace{\left( Z + f'(\omega) \right)}_{f_1}$$

$$\beta = \frac{n_a}{2\pi} r_e \lambda^2 f''(\omega)$$

$n_a$ ... Avogadro constant  
 $r_e$  ... Classical e- radius

Atomic form factor:

$$f(\mathbf{q}, \omega) = \underbrace{f_0(\mathbf{q}) + f'(\omega)}_{f_1} + \underbrace{i f''(\omega)}_{f_2}$$



Snell's law:

$$n \cos \varphi' = \cos \varphi$$

Critical angle:

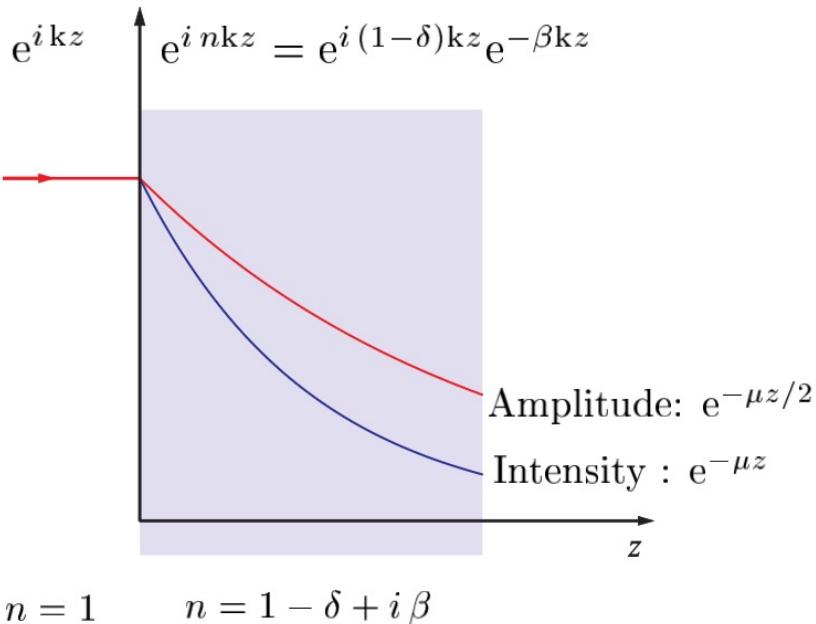
$$\varphi_c = \arccos n \approx \sqrt{2\delta}$$

# Absorption

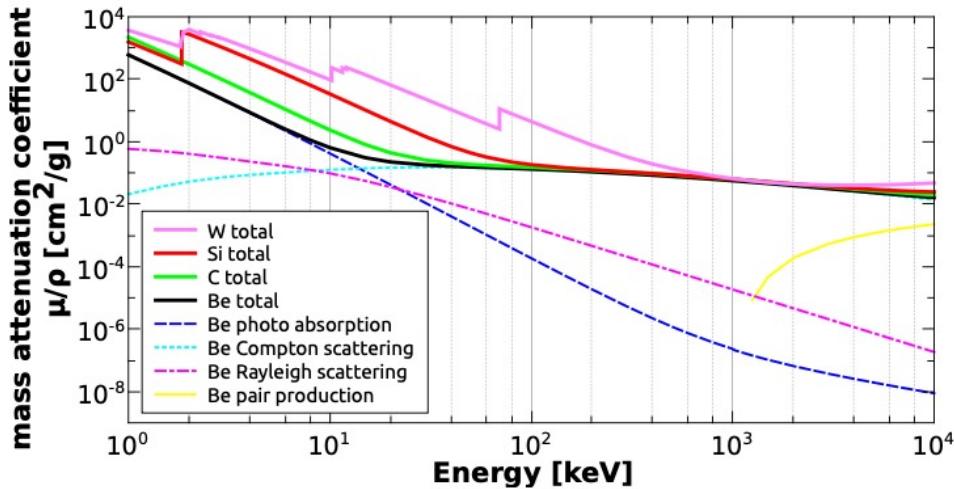
Beer-Lambert law

$$I_{\Delta z}(x, y, z) = I_0 \cdot e^{-\int_{z=0}^{\Delta z} dz \mu(x, y, z)}$$

$$\mu(x, y, z) = \frac{4\pi}{\lambda} \beta(x, y, z)$$



Total attenuation has many contributions:



# Available resources / library packages

Henke online database: <https://henke.lbl.gov>

- only up to 30 keV

NIST / Chantler database: <http://physics.nist.gov/ffast>

- up to 433 keV, inconvenient (only f', f'')

## Python packages

- periodictable
  - only to 30 keV
  - based on Henke tables
- xraylib
  - up to 800 keV
  - bindings to many languages

f'' only photo absorption or total scattering

## Index of Refraction

- Choose from a list of common materials:
- Chemical Formula:
- Density:  gm/cm<sup>3</sup> (enter negative value to use tabulated values.)
- Photon Energy (eV)  Range from  to  in  steps (< 500).  
(NOTE: Energies must be in the range 30 eV < E < 30,000 eV and Wavelengths in the range of .041 nm < Wavelength < 41. nm.)

To request a  press this button:

To reset to default values, press this button: .

Be Density=1.848  
Energy(eV), Delta, Beta  
10000. 3.40754082E-06 1.02839592E-09  
10018.249 3.39512917E-06 1.02188757E-09  
10036.5303 3.38276345E-06 1.01542974E-09  
10054.8457 3.3704423E-06 1.00901842E-09

```
[In [40]: from periodictable import xsf  
  
[In [41]: Be=xsf.index_of_refraction('Be', energy=10)  
  
[In [42]: print(f'delta: {1-np.real(Be)}, beta: {-np.imag(Be)}')  
delta: 3.4075426530444375e-06, beta: 7.985610572831211e-10
```

```
[In [53]: import xraylib  
  
[In [54]: Be=xraylib.Refractive_Index('Be', E=10, density=1.848)  
  
[In [55]: print(f'delta: {1-np.real(Be)}, beta: {np.imag(Be)}')  
delta: 3.4082724095219064e-06, beta: 1.1788936509214389e-09
```

# Typical values for delta/beta and implications for refractive optics

## X rays

- $\delta \sim 10^{-6}$
- focusing lens concave
- focal length 5 km  
for lens with  $R = 1\text{ cm}$



$$f_s = \frac{R}{2\delta}$$

## Visible light

- $|\delta| \sim 0.5$
- focusing lens convex
- focal length 1cm  
for lens with  $R = 1\text{ cm}$



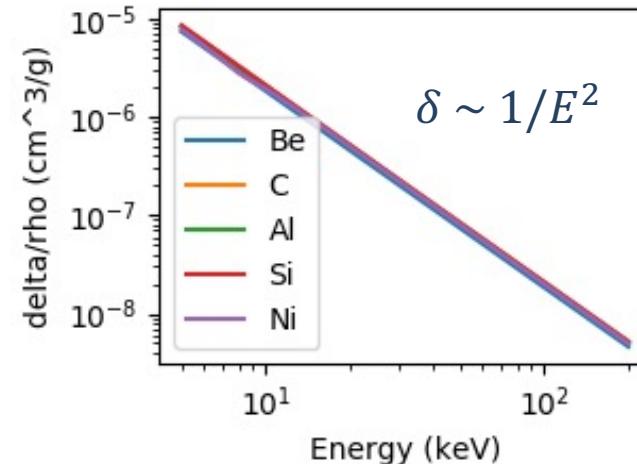
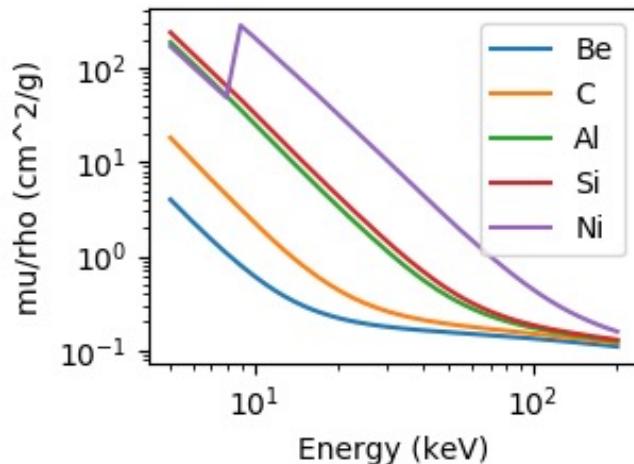
- $\mu \sim 1 - 100\text{ cm}^{-1}$
- attenuation length  $\sim 10 - 0.1\text{ mm}$

- attenuation  $0.001\text{ dB/m}$
- $\mu \sim 0.0002\text{ m}^{-1}$
- attenuation length  $\sim 5\text{ km}$

Refractive x-ray optics face the challenge of very weak refraction  
in combination with strong absorption

# Material considerations for refractive x-ray lenses

- Refractive power only depends on electron density  
 $f_0(q \rightarrow 0) = Z$
- Strong dependence of absorption on atomic number  $Z$   
 $\sigma_{photo} \sim Z^4/E^3$
- Best material: high density  $\rho$ , low atomic number  $Z$ , high purity, fabrication methods



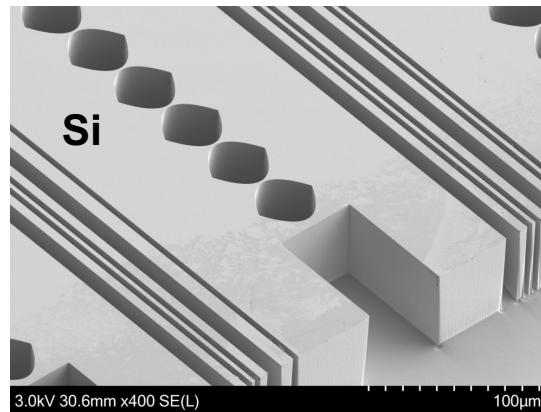
# Design consequences and examples

- Small curvatures R in range  $10 \mu\text{m} - 1000 \mu\text{m}$
- Stacking of multiple lenses

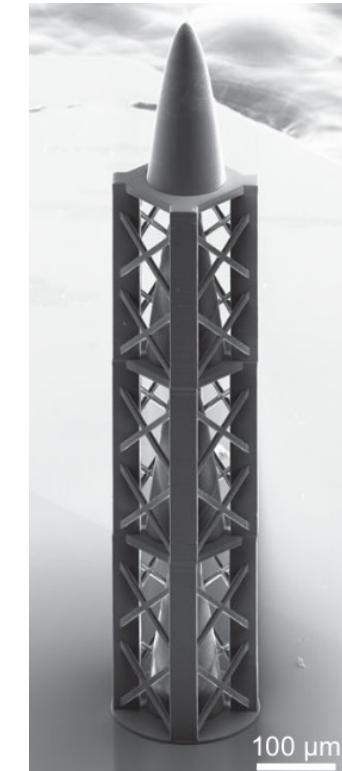
Individually packaged,  
coin-shaped lenses  
Be, Al, C\*



Etched one-dimensional lenses  
Si, SiC, C\*



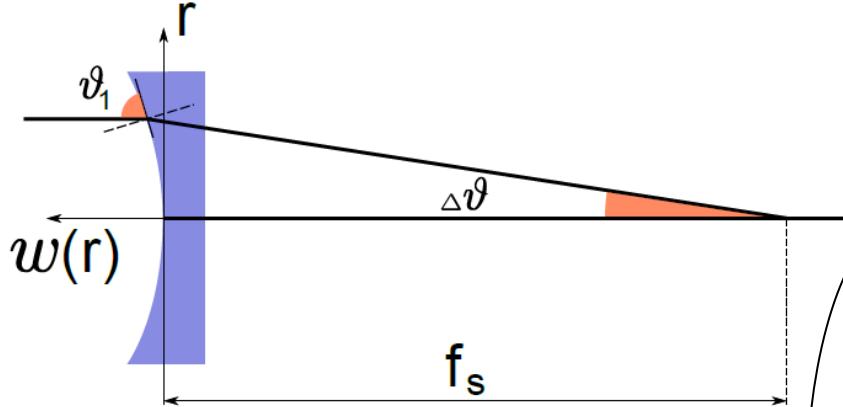
Printed/lithographic  
plastic lenses



Kubec et al., Nat. Commun. 13(1), (2022)

# Lens shape

Refraction on single surface into common focal point:



thin lens  
 $w(r) \ll f_s$

$$\frac{r}{f_s} = \delta \frac{dw}{dr}$$

$$\Delta\vartheta = \delta \cot \vartheta_1 = \delta \tan(90^\circ - \vartheta_1) = \delta \frac{dw}{dr}$$

$$\cos \vartheta_1 = (1 - \delta) \cos (\vartheta_1 - \Delta\vartheta)$$

paraxial approximation

- $\cos(\vartheta_1 - \Delta\vartheta) = \cos(\vartheta_1) \cos(\Delta\vartheta) + \sin(\vartheta_1) \sin(\Delta\vartheta)$
- $\delta \sin(\vartheta_1) \Delta\vartheta = 0$

$$\cancel{\Delta\vartheta}$$

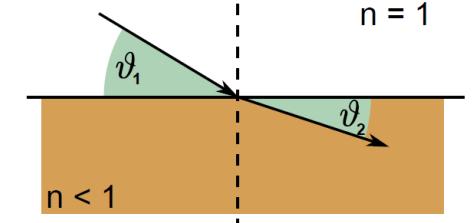
$$\cancel{\Delta\vartheta}$$

$$w(r) = \frac{r^2}{2f_s\delta} + c$$

Curvature definition:

$$\frac{d^2 w}{dr^2} = \frac{1}{f_s\delta} \equiv \frac{1}{R}$$

Snell's law:



$$n_1 \cos \vartheta_1 = n_2 \cos \vartheta_2$$

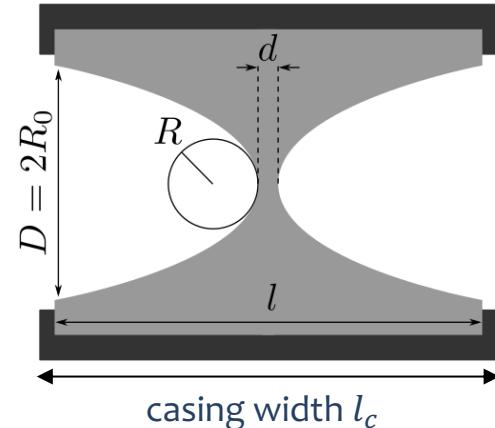
# Basic lens properties

- Focal length:  
N... Number of lenses

$$f_N = \frac{R}{2N\delta}$$

- Diffraction-limited spot size:  $d_t = \alpha \cdot \frac{\lambda}{2NA} = \alpha \cdot \frac{\lambda f}{D_{\text{eff}}}$

$\alpha$ ... aperture-shape dependant: 1.22 (disc) – 0.75 (Gaussian)  
NA... numerical aperture



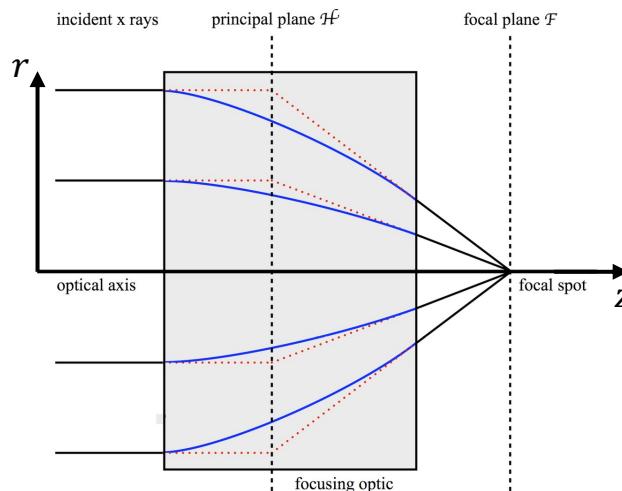
- Effective aperture:  $D_{\text{eff}} = \sqrt{\frac{1 - e^{-a_p}}{a_p}} 2R_0$   $a_p = \frac{\mu N R_0^2}{2R}$
- Transmission (2D lens):  $T_p = \frac{1 - e^{-2a_p}}{2a_p} e^{-\mu N d}$

# Thick lens

Defining refractive power:  $\omega = \sqrt{\frac{1}{f_s l}}$

Solving harmonic differential equation, boundary conditions:  $r(0) = r_0, r'(0) = 0$

$$\frac{d^2}{dz^2}r(z) = -\omega^2 r(z) \quad \longrightarrow \quad r(z) = r_0 \cdot \begin{cases} 1 & : z \leq 0 \\ \cos(\omega z) & : 0 \leq z \leq L \\ b + mz & : L \leq z \end{cases}$$



$$\begin{aligned} b &= \cos(\omega L) + \omega L \sin(\omega L) \\ m &= -\omega \sin(\omega L). \end{aligned}$$

Principal plane  $\mathcal{H}$ :  $b + m z_H = 1$

Focal plane  $\mathcal{F}$ :  $b + m z_F = 0$

# Thick lens

Principal plane location:

$$z_H = L + \frac{\cot(\omega L)}{\omega} - \frac{1}{\omega \sin(\omega L)}$$

Focal length  $f = z_F - z_H$ :

$$f = \frac{1}{\omega \sin(\omega L)}$$

Critical lens length, if converging ray intersects optical axis:  $\cos(\omega L) = 0$ , i.e.  $\omega L \geq \pi/2$

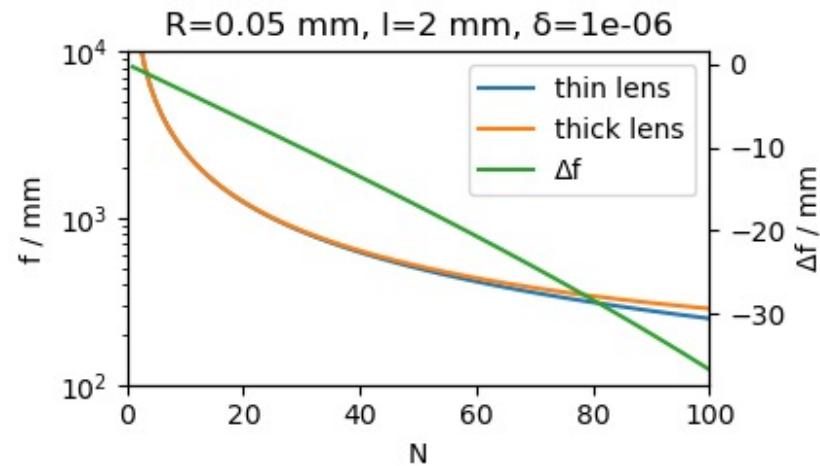
$$L_c = \frac{\pi}{2\omega}$$

$$f_{min} = \frac{1}{\omega \sin(\omega L_c)} = \frac{1}{\omega} = \sqrt{f_s l} = \sqrt{\frac{Rl}{2\delta}}$$

Focal plane location:

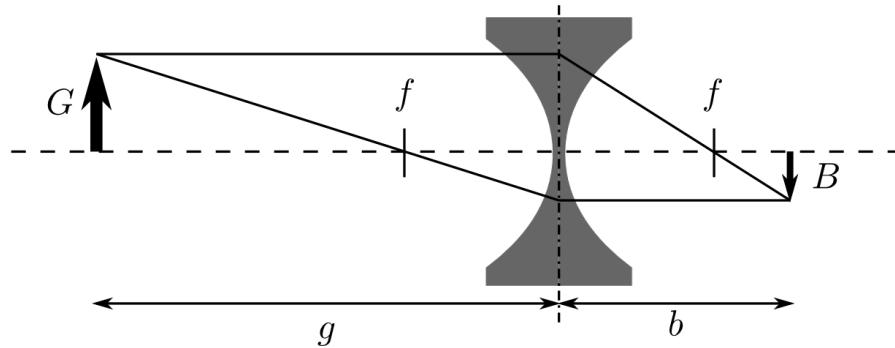
$$z_F = L + \frac{\cot(\omega L)}{\omega}$$

14



# Focus size

Convolution between geometric image size  $B$  and diffraction-limit  $d_t$



$$\text{Lens equation: } \frac{1}{g} + \frac{1}{b} = \frac{1}{f}$$

$$\text{Image size } B: \quad B = G \cdot \frac{b}{g}$$

$$\text{Total image size } B_t = \sqrt{B^2 + d_t^2}$$

Two contributions:

- Geometric demagnification of source
- Diffraction effects

$$\text{Beam caustic: } B_t(z) = \sqrt{B_t^2 + 0.5 \ln(2) D_{eff}^2 \left(\frac{z}{b}\right)^2}$$

Two contributions:

- Focus size
- Lens aperture / divergence

# Reverse calculation for desired focal length / image distance

Focal length  $f$  for given image distance  $b$ :

$$\frac{1}{g} + \frac{1}{b} = \frac{1}{f} \longrightarrow f = \frac{bg}{b+g}$$

Required number of lenses  $N$ :

$$f_N = \frac{R}{2N\delta} \longrightarrow N = \frac{R}{2f\delta}$$

$$f = \frac{1}{\omega \sin(\omega L)} \longrightarrow N = \frac{1}{\omega L} \arcsin\left(\frac{1}{f\omega}\right)$$

# Analytic online calculator

DESY lenscalc: <http://lenscalc.desy.de>

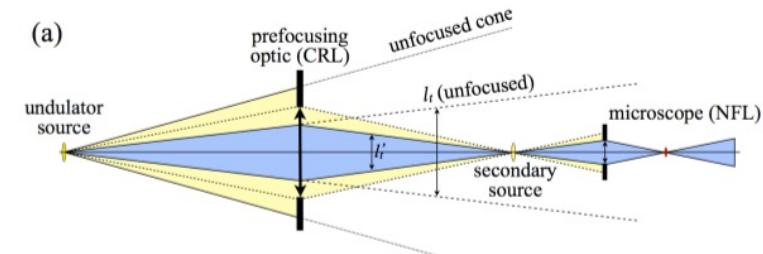
Covers:

- 2D Focusing (i.e. CRL)
- Crossed 1D focusing (i.e. NFL)
- Combination with 1D / 2D prefocusing

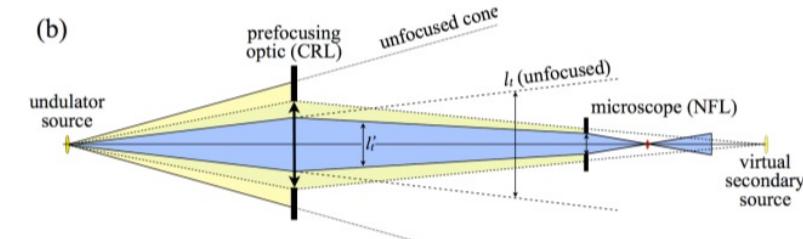
Assumptions/Limitation:

- Beam divergence is neglected
- Full illumination / overfill of lenses
- Gaussian source
- No spatial filtering for prefocus  
(coherence independent of lens aperture size)

Real secondary source:



Imaginary secondary source:

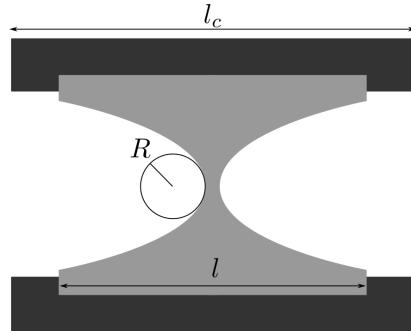


Calculations can be shared/saved with link

# Focal spot limit

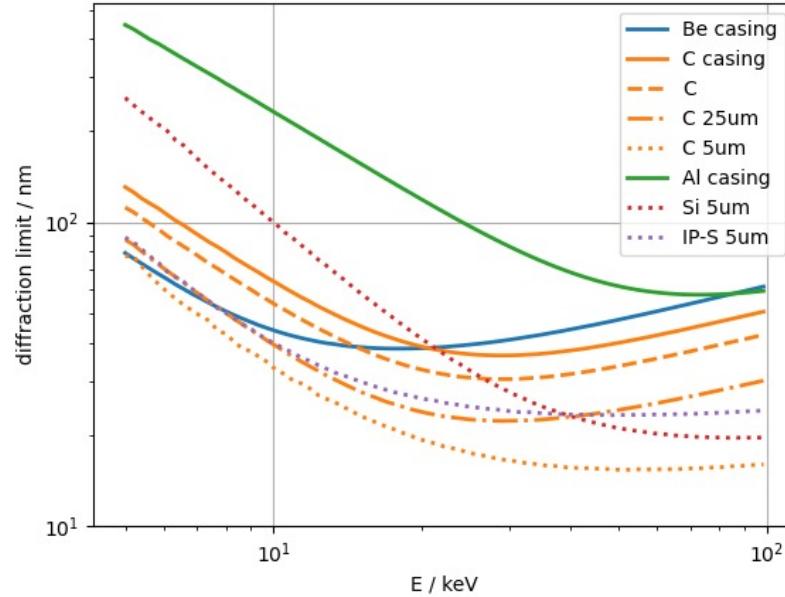
## Desirable lens properties

- Fabrication of small curvatures
- Large lens stacks possible
- Minimize gap between lenses:  $l_c \approx l$



$$f_{\min} = \sqrt{\frac{Rl_c}{2\delta}}$$

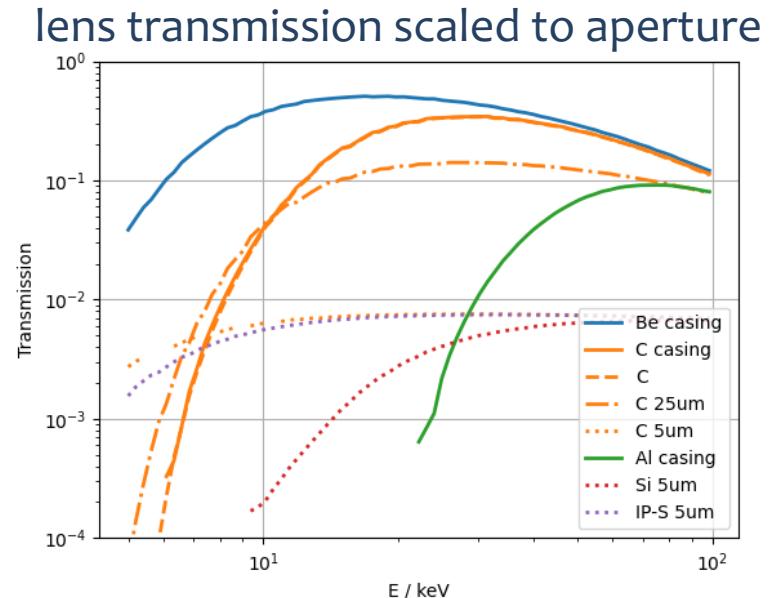
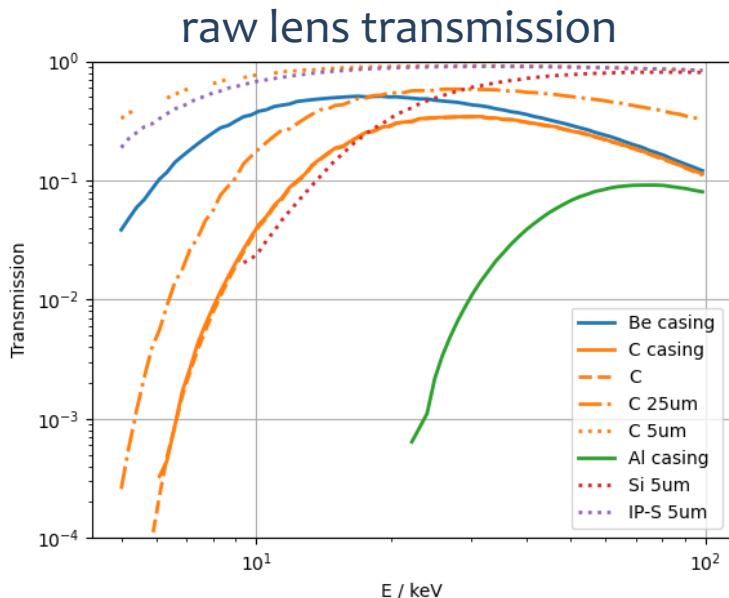
## achievable focal spot size



Be/Al/C: 1 mm substrate, 2 mm casing,  $R = 50 \mu\text{m}$   
Si/IP-S: 40  $\mu\text{m}$  aperture,  $R = 5 \mu\text{m}$   
Working distance  $\geq 10 \text{ mm}$

# Performance for 100 nm focus

- Reduced transmission with diamond compared to beryllium
- Etched/printed lenses only viable, if beam can be tuned to aperture
- Large aperture lenses only viable, if lateral coherence high enough

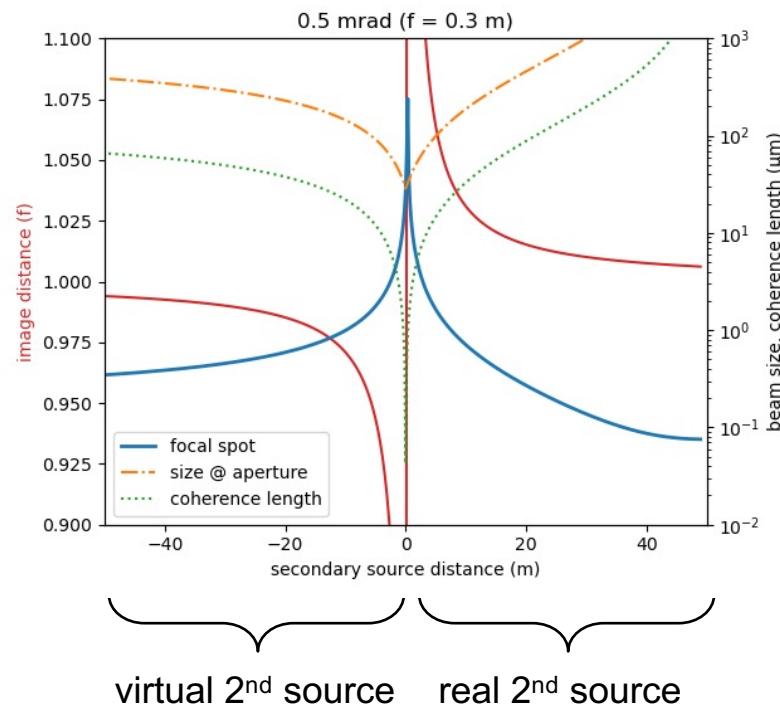
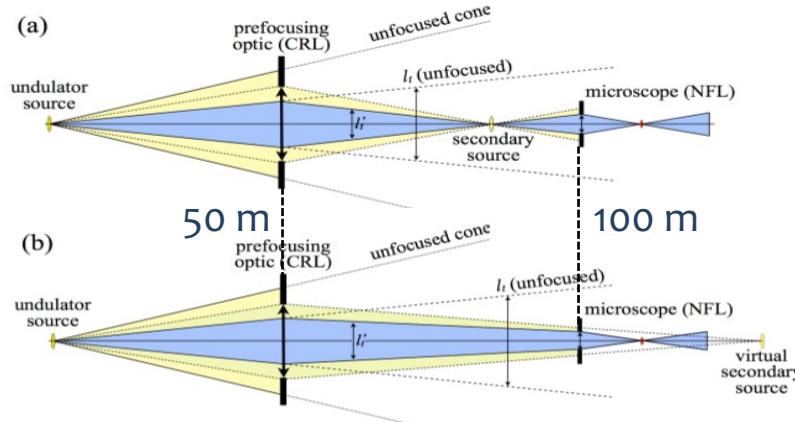


# Example: Zoom lens system

Limits for flexible focal spot size change with 2-stage focusing at Petra IV

## Conditions

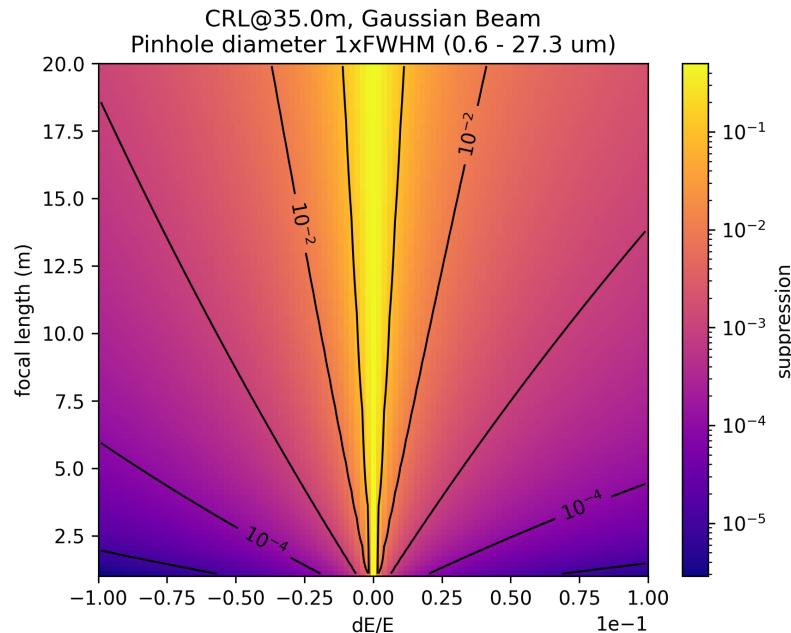
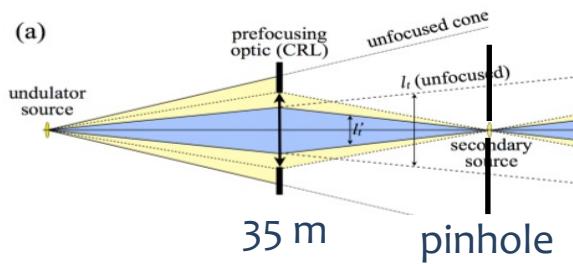
- Prefocus at 50 m
- Full beam on prefocusing lens (0.7 mm)
- Experiment / main lens at 100 m
- Main lens: 300  $\mu\text{m}$  aperture,  $f = 0.3 \text{ m}$



# CRL as monochromator

## Setup

- CRL @ 35 m, aperture matching beam size
- Variable focal length 1 m – 20 m
- Pinhole in focus for  $dE/E = 0$
- Pinhole size = FWHM focus size



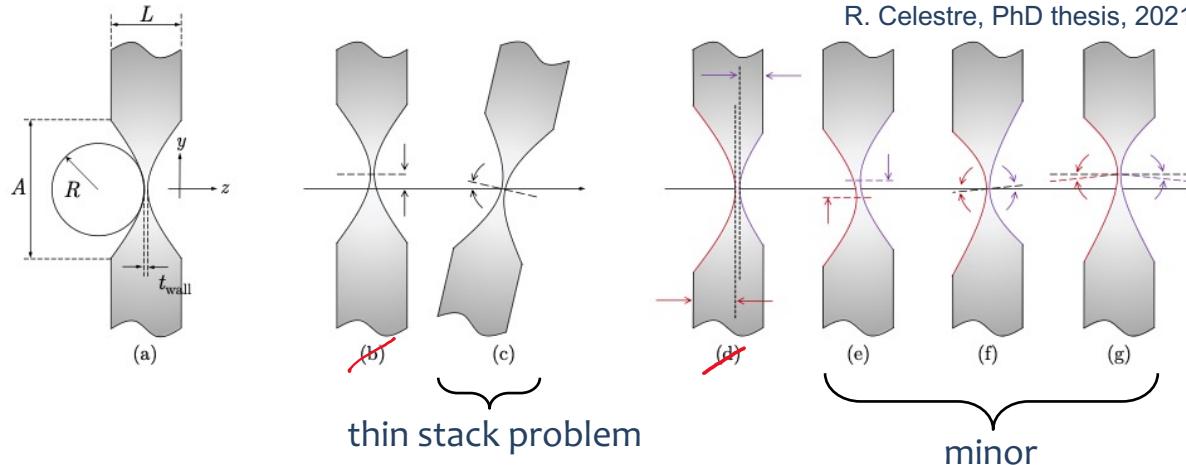
Beam caustic:  $B_t(z) = \sqrt{B_t^2 + 0.5 \ln(2) D_{eff}^2 \left(\frac{z}{b}\right)^2}$

# Lens errors and aberration measurement / compensation

# Lens aberration, wavefront measurements

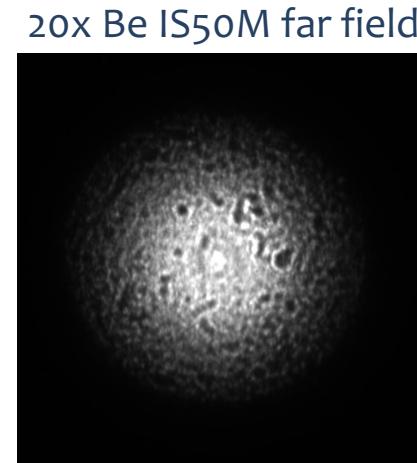
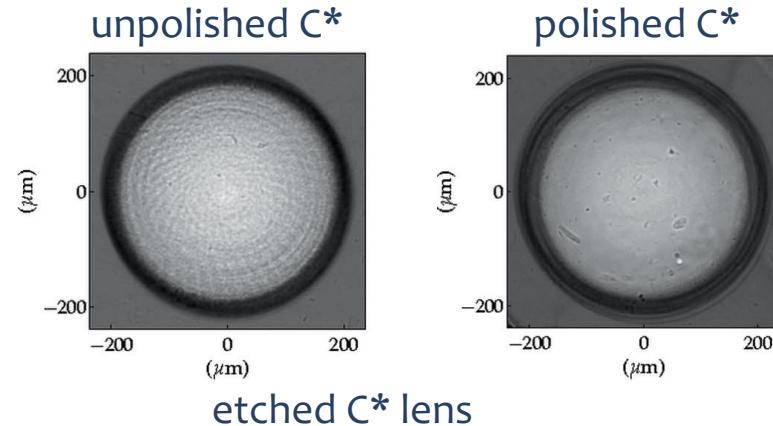
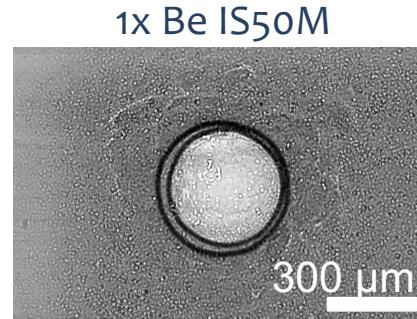
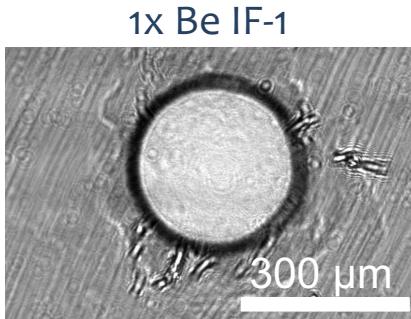
Not discussed here: Induced aberration due to mechanical misalignment

- Transverse position error (stacking errors or lens eccentricity)
- Tilt errors



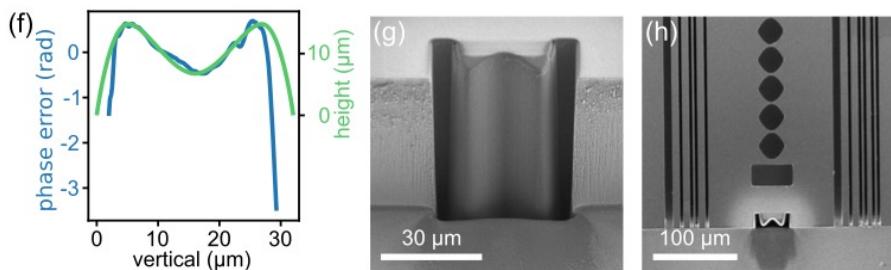
Focus on lens error due to fabrication limitations to create a parabolic lens shape.

# High-frequency errors and material defects

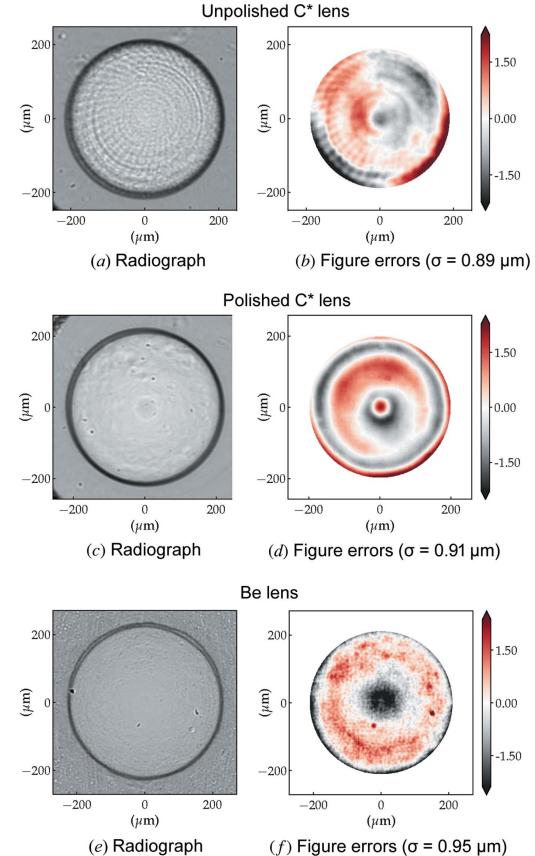


# Typical fabrication errors

- ~~Stamp positioning/guiding errors~~
- Stamp to press metallic lens deformed
- Metallic material relaxes after pressing
- Ablation process unstable / random
- Laser positioning errors
- Etching errors: Slanted side wall, under-etched mask



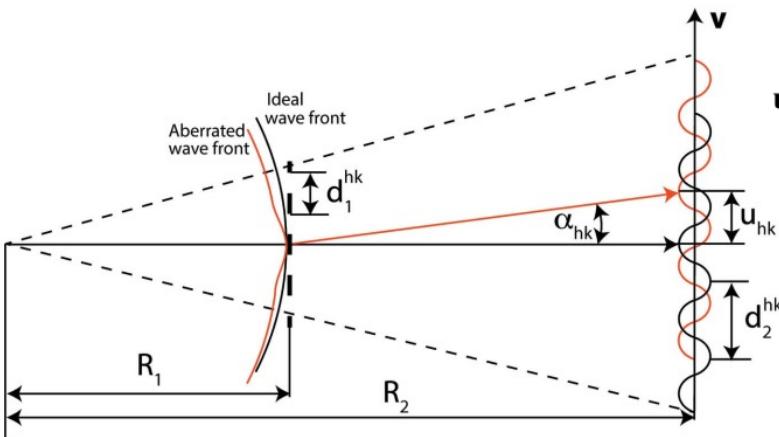
Seiboth et al., Appl. Phys. Lett. 122(24), (2023)



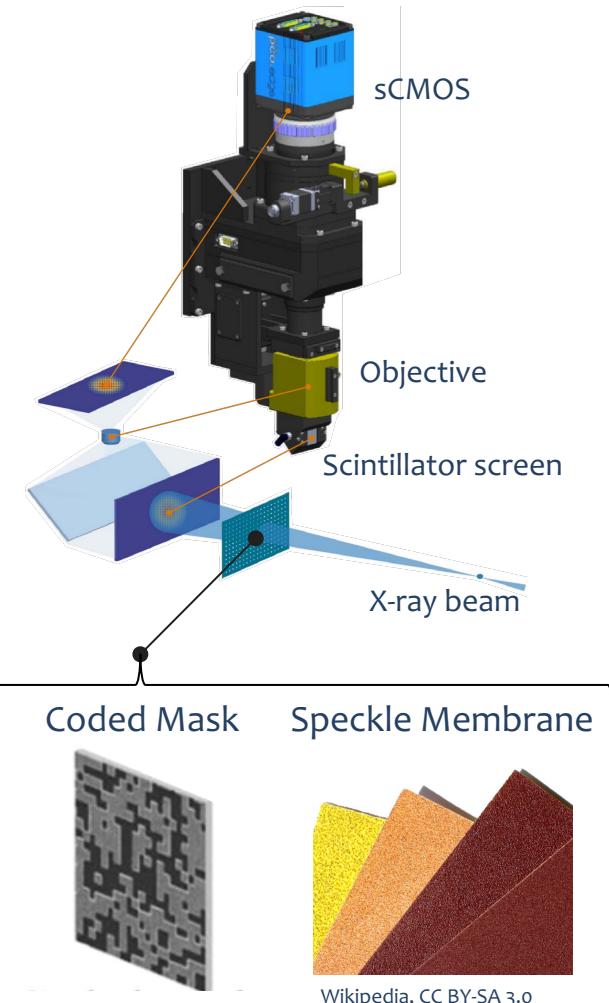
Celestre et al., J. Synchrotron Rad. 29, 629-643 (2022)

# Near-field measurements

- Typically based on phase contrast
- Low coherence requirements
- Flat and divergent beams
- Displacement of features  $\mathbf{u}$  → Phase gradient  $\nabla\phi$



$$\mathbf{u}(\mathbf{r}) \simeq \frac{\lambda}{2\pi} \frac{R_2}{R_1} (R_2 - R_1) \nabla\phi_a(\mathbf{r})$$



Liu et al., J. Synchrotron Rad. 27(2), 2020

Seaberg et al., J. Synchrotron Rad. 26(4), 2019

Frith et al., Rev. Sci. Instrum. 94(4), 2023

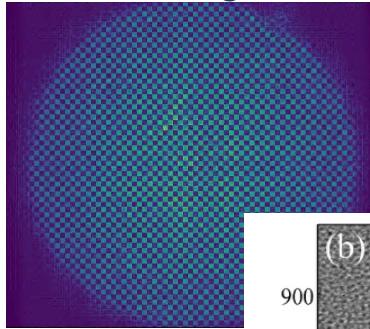
Berujon et al., J. Synchrotron Rad. 22(4), 2015

# Near-field measurements

Feature size and contrast on detector depend on:

- Pattern feature size
- Pattern feature phase shift
- Pattern – Detector distance

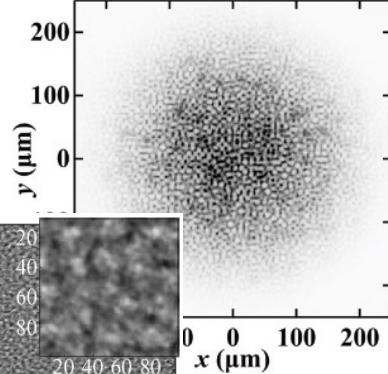
Grating



(b)  
900  
600  
300

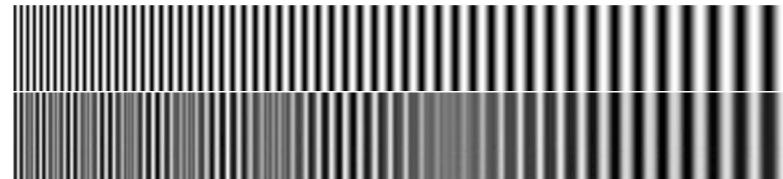
Speckle Membrane

Coded Mask

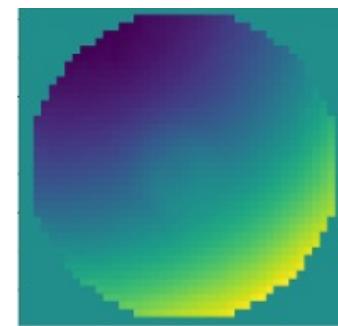


Feature displacement  
in x/y direction

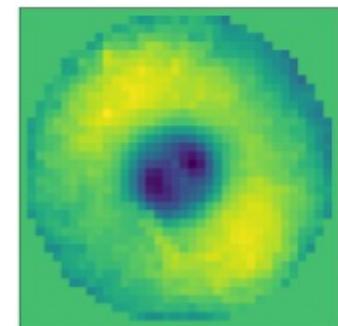
modulation transfer of phase contrast



x/y phase gradient



Phase error

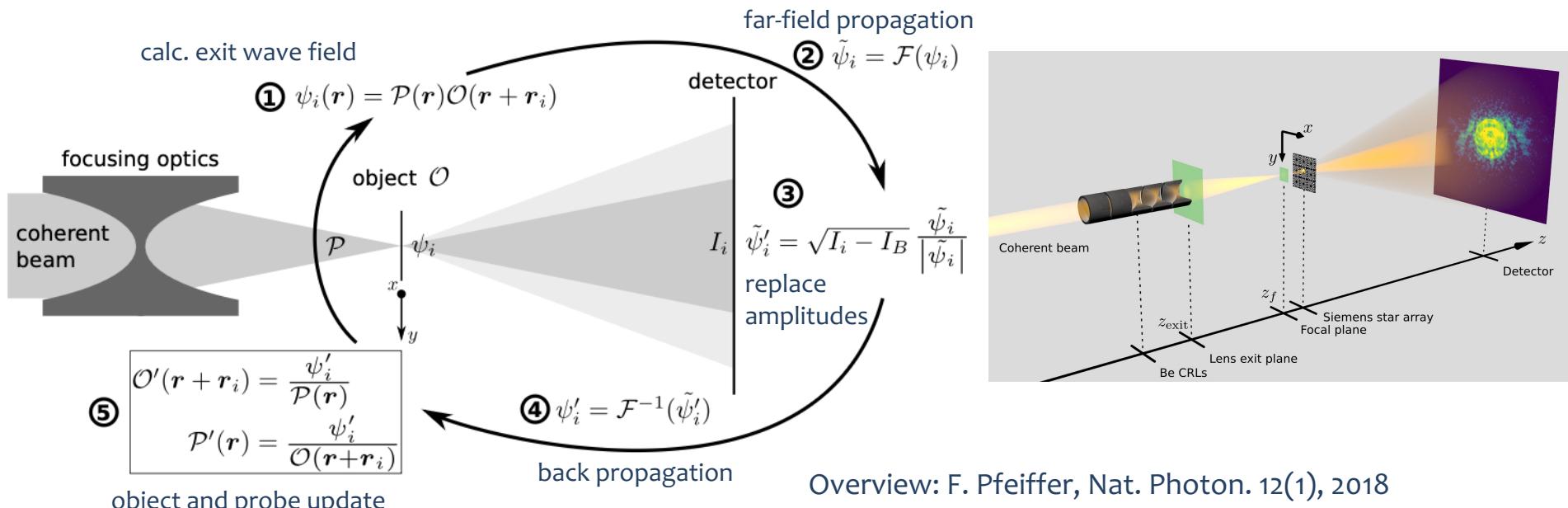


Numerical integration

- least-square minimization
- Fourier transform based

# Far-field measurements

- Ptychography: Coherent scanning method, requires a confined beam
- Arbitrary test object: Strong phase shift and diverse feature orientation optimal
- Far-field detector: High dynamic range, low noise, and small pixelsize



# Phase plate design

1-2: Wave field retrieval (see slides before):  $\psi$

3:

- Reconstructed wavefield is numerically propagated (Fresnel propagator)

$$\psi_{exit} = \mathbb{K}_{\Delta z} \psi$$

- Removal of spherical wave and other unrelated phase errors (i.e. tilt)

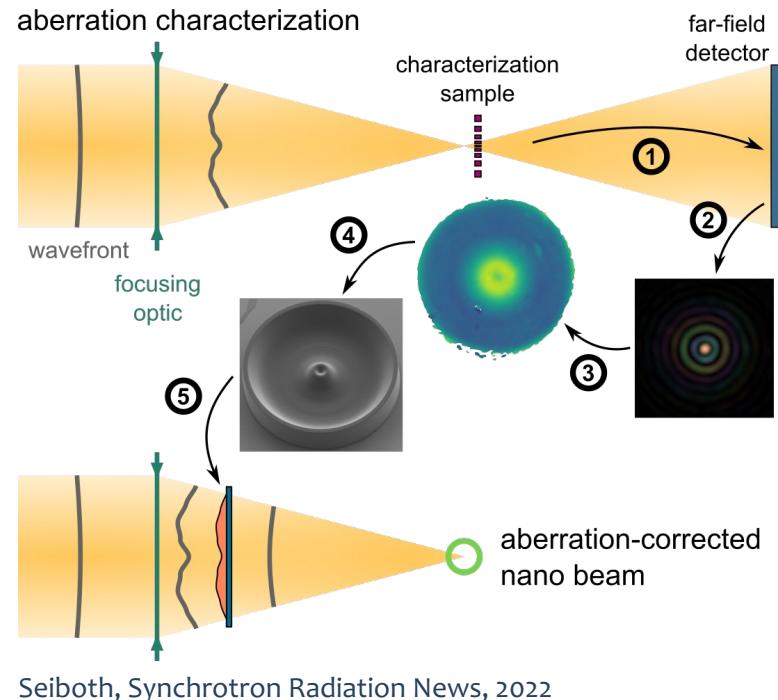
$$\psi_{\varepsilon} = \psi_{exit} e^{-ik(\sqrt{\Delta z^2 + x^2 + y^2} - \Delta z)}$$

4:

- Conversion of phase shift into height profile

$$\arg(\psi_{\varepsilon}) = -\varphi_{PP} = k\delta z_{PP}$$

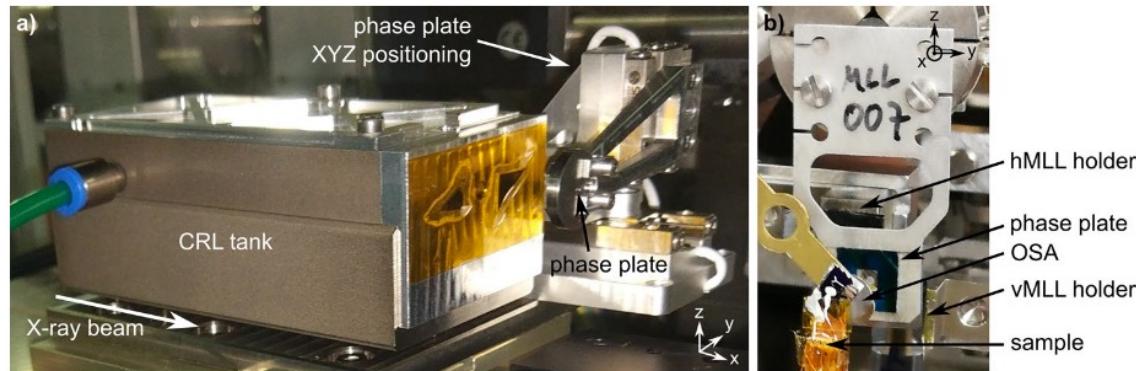
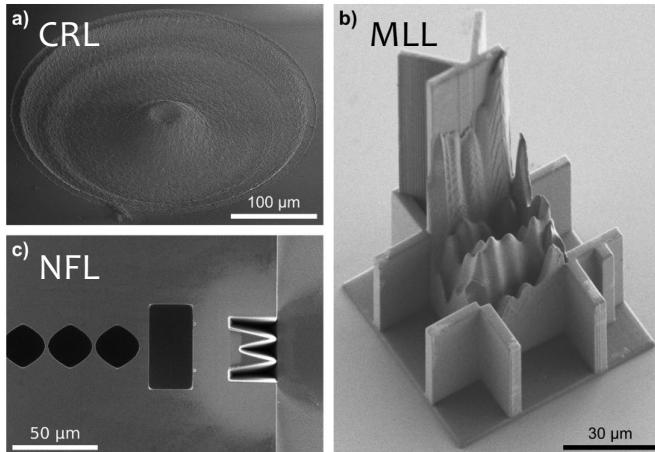
5: Install and align



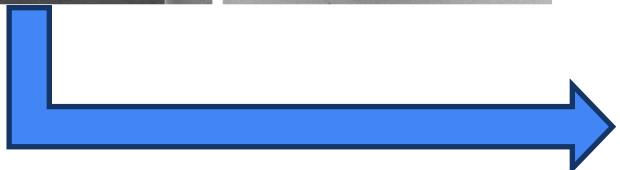
Seiboth, Synchrotron Radiation News, 2022

# Alignment...

- Positioning requirements depend on frequency of aberration features
- CRL typical:  $< 5 \mu\text{m}$

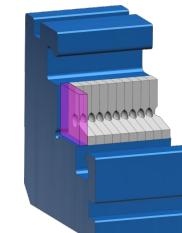
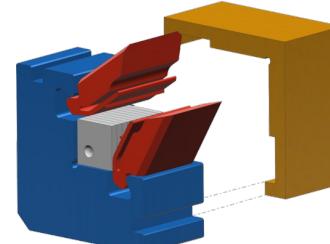


Seiboth, Synchrotron Radiation News, 2022



Lens Cube

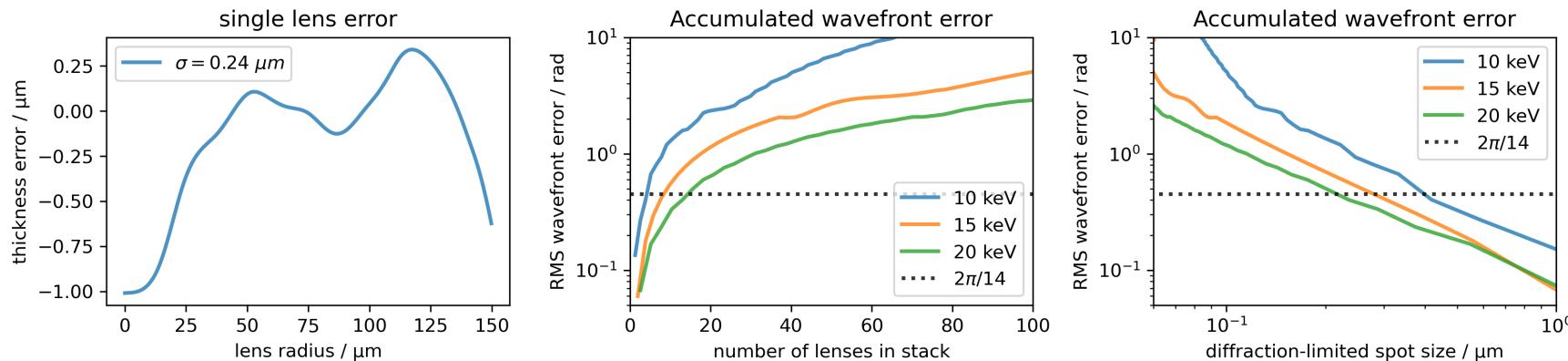
Pre-aligned, monolithic assembly  
concept for large-aperture CRLs:



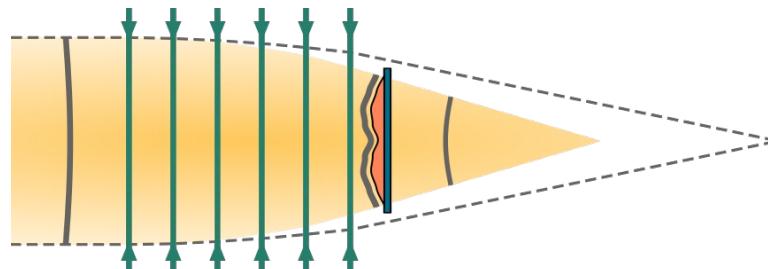
Wang et al., Opt. Express 33(11), 2025

# Aberration compensation is required for sub-micron beams

Numerical example with a typical CRL error profile for  $R = 50 \mu\text{m}$  /  $D = 300 \mu\text{m}$  lenses



Downstream mounted phase plate: Measurement possible, chromatic problems

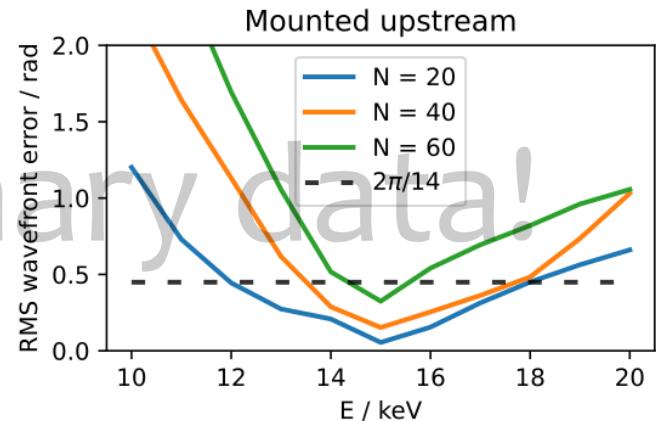
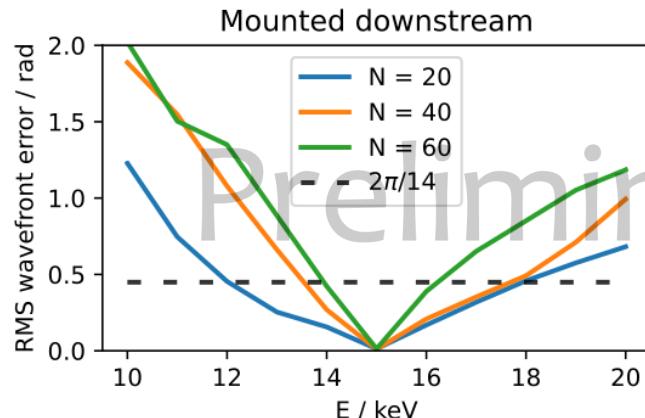
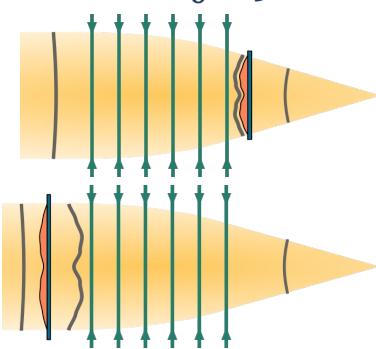


Energy change leads to change in

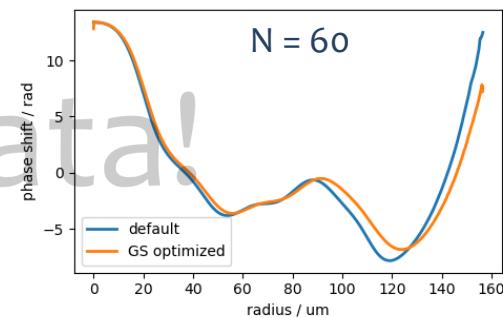
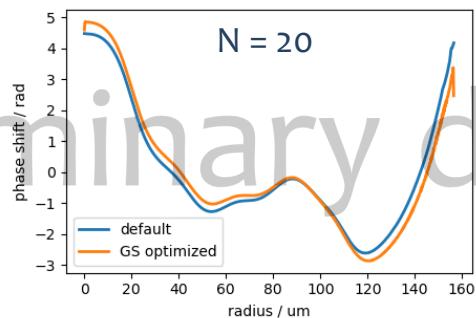
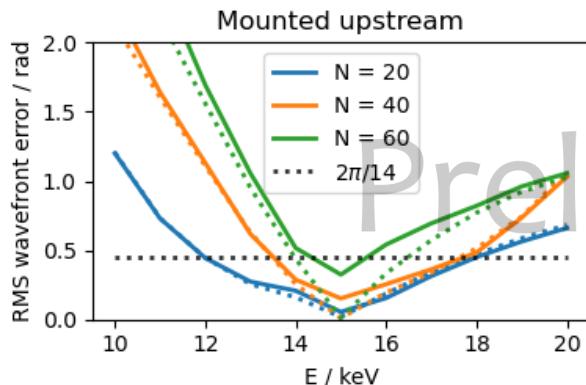
- Beam convergence
- Aberration signature
- Beam size

# Behavior of upstream vs. downstream phase plates

- PP for  $E_0=15$  keV



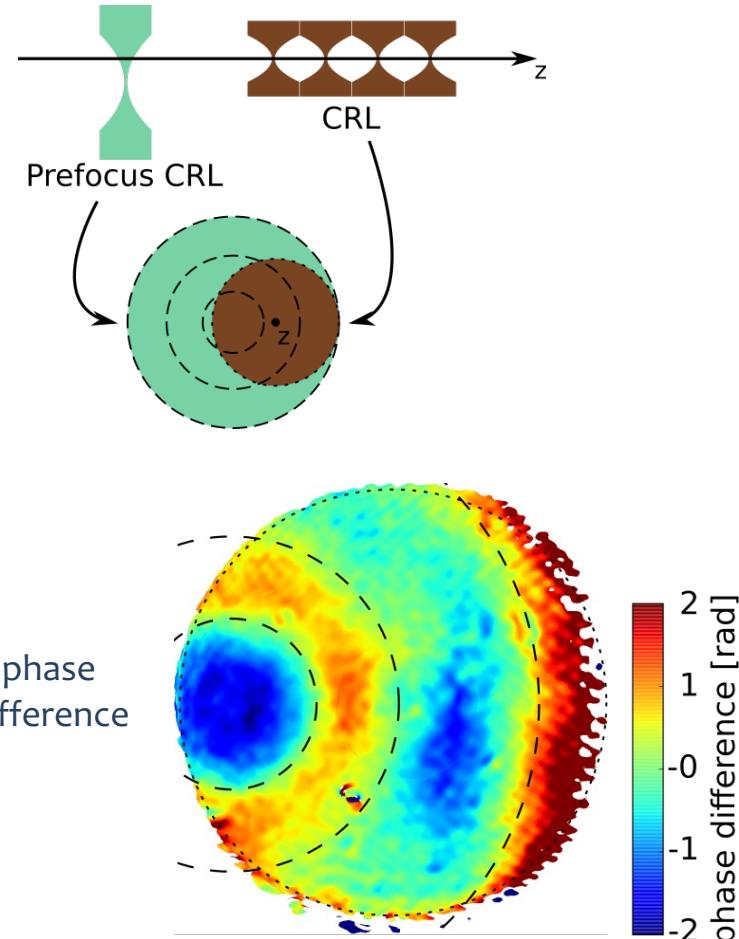
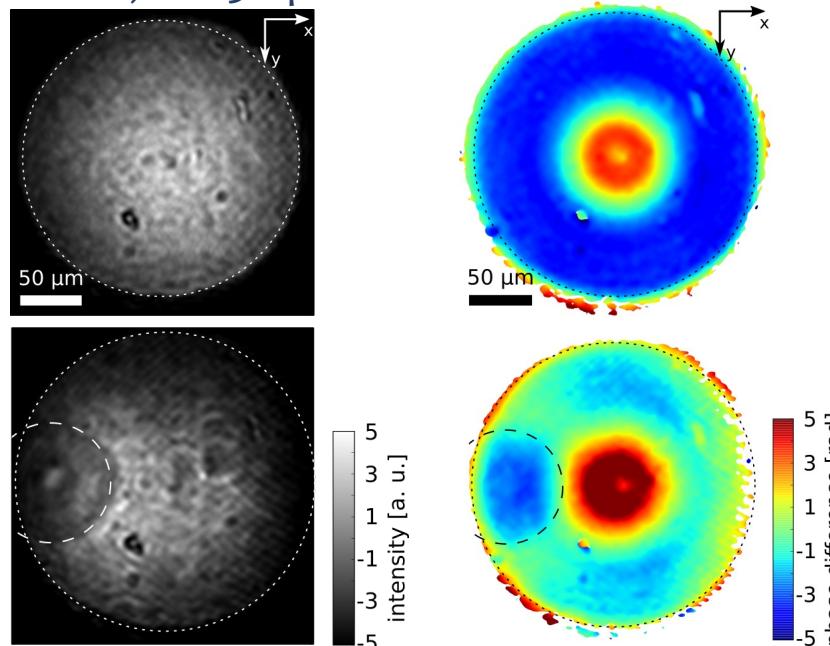
- Upstream phase plate optimized with GS algorithm (dashed lines)



# Influence of upstream optics

Example for prefocusing at LCLS / MEC

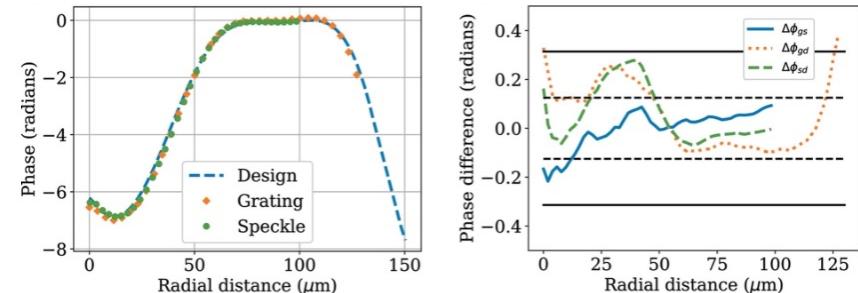
- $E = 8.2 \text{ keV}$
- $N = 7, R = 500 \mu\text{m}$  CRLs 4 m upstream
- $N = 20, R = 50 \mu\text{m}$  CRLs



# Conclusions

- Analytical calculations give valuable estimations and boundary conditions
- First guess for setting up a beamline on Oasys
- Lens equation applicable to other imaging optics
- Aberrations of a beamline / optical components can be measured by various methods
- Confidence in measurements / results needs to be established
- Alignment is crucial

# Questions?



Seaberg et al., J. Synchrotron Rad. 26(4), 2019